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(12) United States Design Patent

Ikeda

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(54) **TEMPERATURE PROBE HANDLE**

(76) Inventor: **John K. Ikeda**, 4357 NE. 57th, Seattle, WA (US) 98105

(**) Term: **14 Years**

(21) Appl. No.: **29/208,387**

(22) Filed: **Jun. 28, 2004**

(51) **LOC (6) Cl.** **10-04**

(52) **U.S. Cl.** **D10/60**

(58) **Field of Search** D10/57, 60; D8/303, D8/307, 310–320; 374/208–209

(56) **References Cited**

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Primary Examiner—Antoine D. Davis

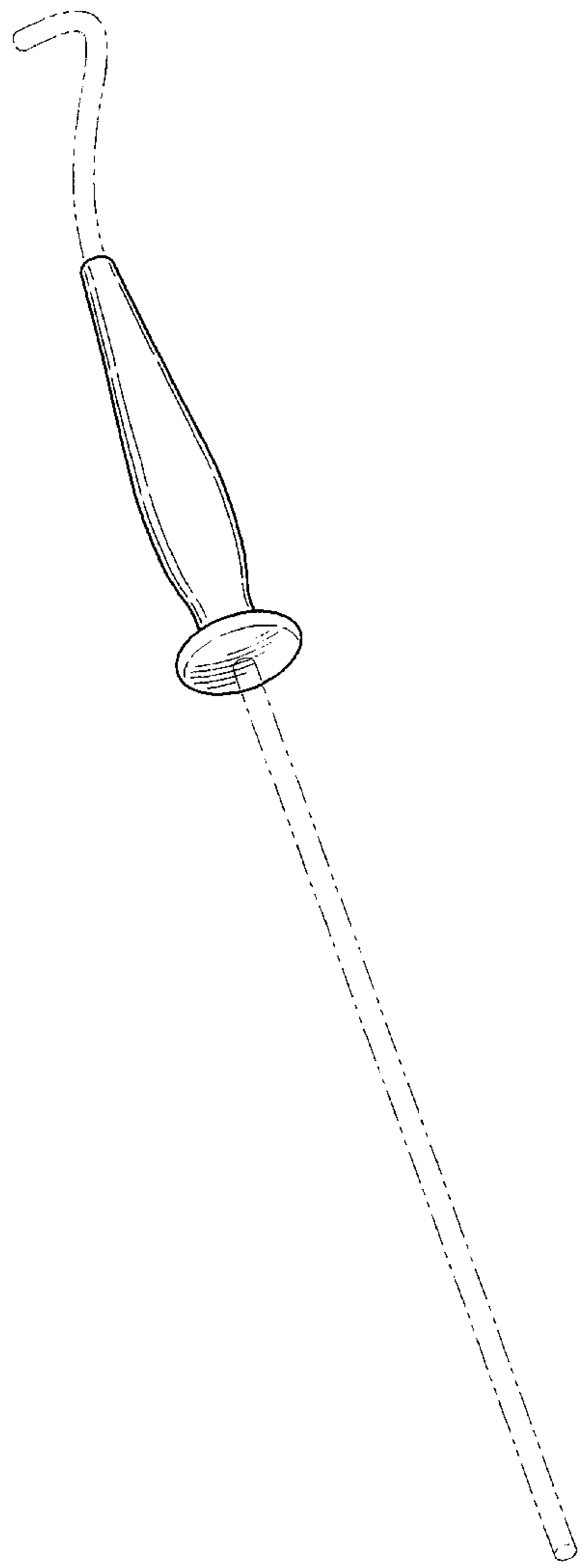
(57) **CLAIM**

The ornamental design for a temperature probe handle, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a temperature probe handle showing my new design;
FIG. **2** is a front plan view thereof;
FIG. **3** is a right side elevation view thereof;
FIG. **4** is a left side elevation view thereof;
FIG. **5** is a rear plan view thereof;
FIG. **6** is a top elevation view thereof; and,
FIG. **7** is a bottom elevation view thereof.
The broken line showing is for illustrative purposes only and forms no part of the claimed design.

1 Claim, 3 Drawing Sheets



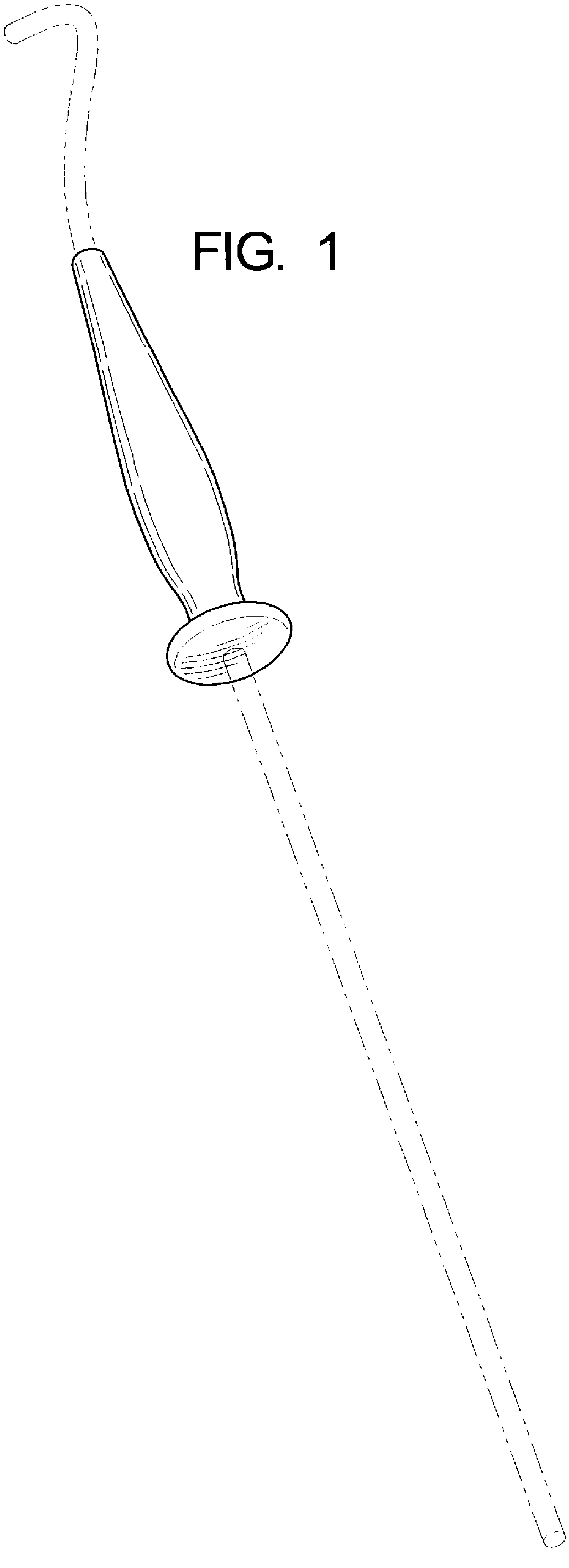


FIG. 1

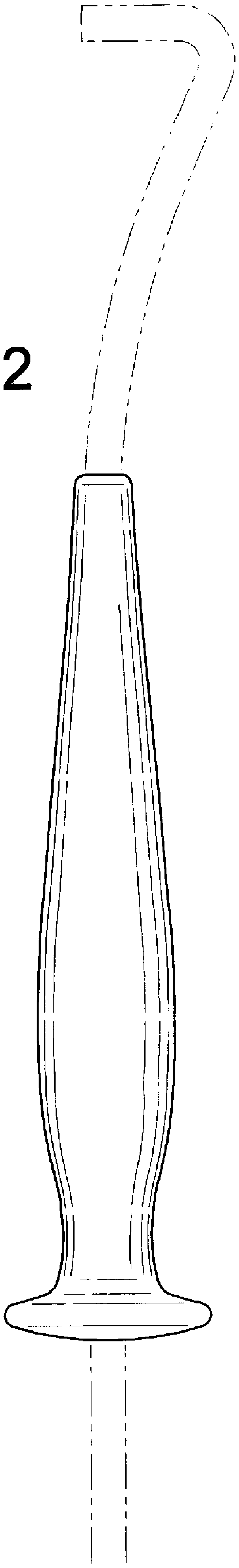


FIG. 2

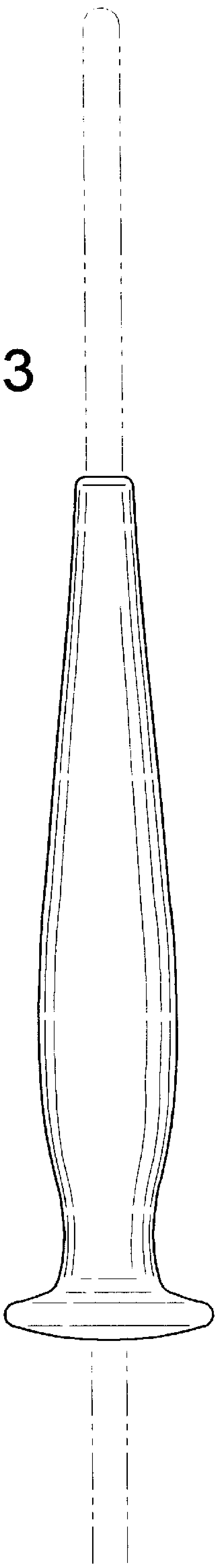


FIG. 3

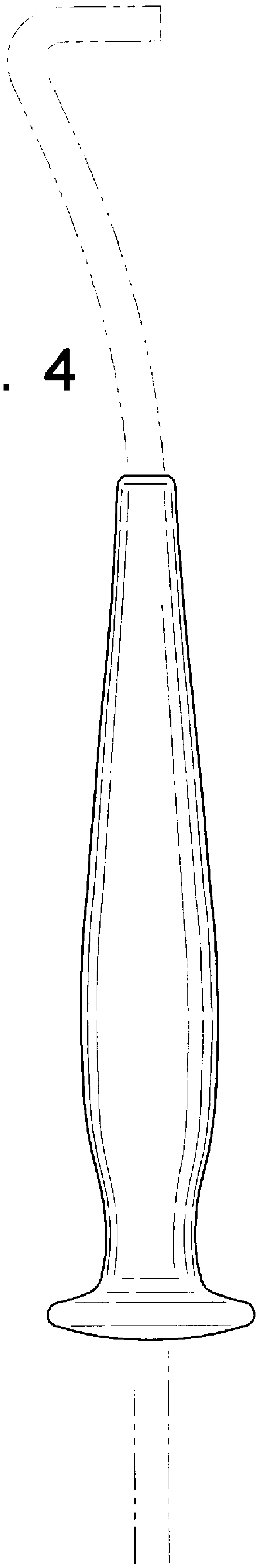


FIG. 4

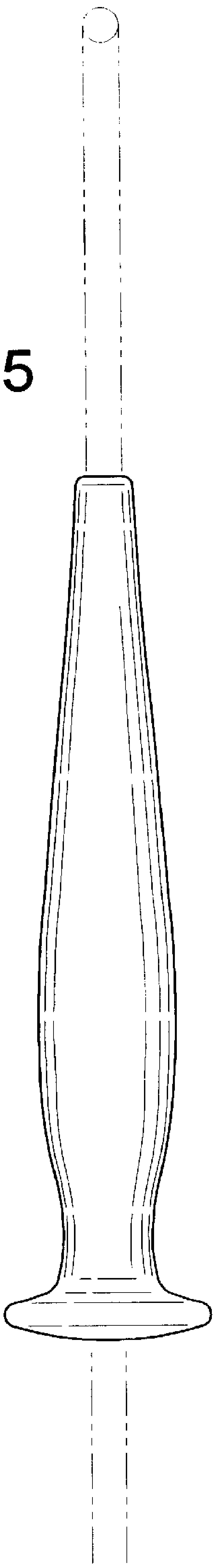


FIG. 5

FIG. 6

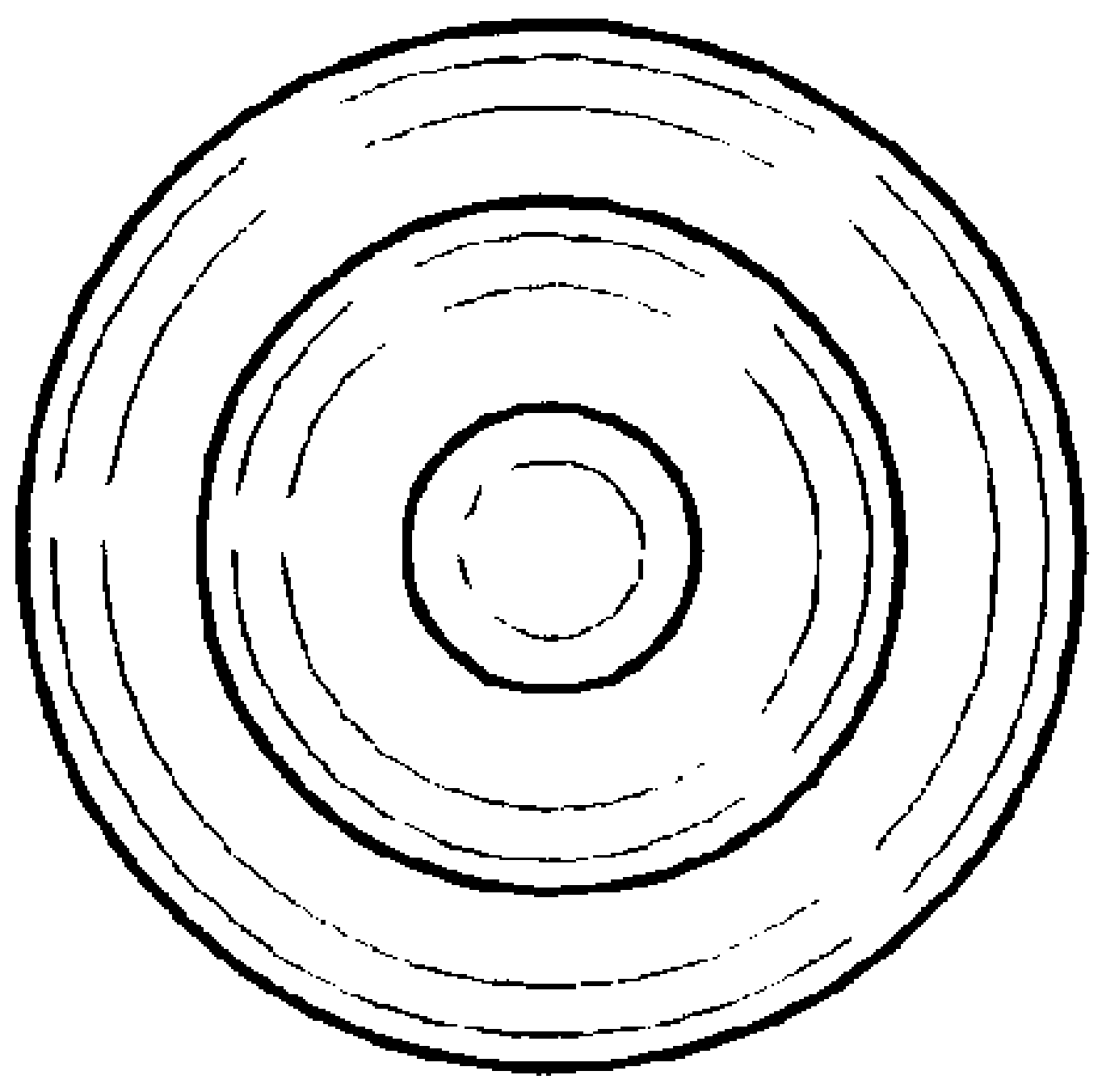


FIG. 7